

## Notice of References Cited

Application/Control No.

10/067,608

Applicant(s)/Patent Under Reexamination CHI ET AL.

Examiner

CongVan Tran

Art Unit

2683

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,600,772	07-2003	Zeira et al.	375/130
	В.	US-6,373,823	04-2002	Chen et al.	370/252
٠,,,	·C	, US-6,697,634 ✓	02-2004	Hayashi, Masaki	455/522
•	D	US-6,334,047 v	12-2001	Andersson et al.	455/69
·	E	US-6,163,705	12-2000	Miya, Kazuyuki	455/522
	F	US-6,556,839	04-2003	Kondo, Takayuki	455/522
	G	US-6,405,052	06-2002	Faber, Ulrich	455/522
	н	US-2001/0029189	10-2001	Mandyam, Giridhar D.	455/522
	1	US-2001/0008524 >	07-2001	Ishii et al.	370/335
	J	US-2002/0021682 •	02-2002	Ariyoshi et al.	370/335
	к	US-2003/0022630 -	01-2003	Gandhi et al.	455/69
	Ĺ	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Ρ					
	σ					
	R					
	Ø			·		
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.